

# N-Channel Enhancement Mode Power MOSFET

#### Description

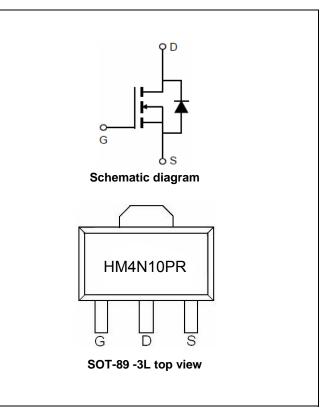
The HM4N10PR uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

- $V_{DS} = 100V, I_D = 4A$   $R_{DS(ON)} < 160m\Omega @ V_{GS} = 10V$  (Typ:136m $\Omega$ )  $R_{DS(ON)} < 170m\Omega @ V_{GS} = 4.5V$  (Typ:140m $\Omega$ )
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

#### Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



#### Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM4N10PR	NHM4N10PR	SOT-89-3L	Ø330mm	12mm	2500 units

#### Absolute Maximum Ratings (T<sub>A</sub>=25℃ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	100	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	I <sub>D</sub>	4	A
Drain Current-Pulsed (Note 1)	I <sub>DM</sub>	20	A
Maximum Power Dissipation	PD	1.5	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>STG</sub>	-55 To 175	°C

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Ambient (Note 2)	R <sub>0JA</sub>	100	°C/W
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#### Electrical Characteristics (T<sub>A</sub>=25<sup>°</sup>C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	100	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS}$ =100V, $V_{GS}$ =0V	-	-	1	μA



# HM4N10PR

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Gate-Body Leakage Current	I <sub>GSS</sub>	$V_{GS}$ =±20V, $V_{DS}$ =0V	-	-	±100	nA
On Characteristics (Note 3)						•
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	1.0	1.5	2.0	V
Durain Courses On State Desistance		V <sub>GS</sub> =10V, I <sub>D</sub> =4A -		136	160	
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =4A	-	140	170	mΩ
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =5V,I <sub>D</sub> =4A	-	5	-	S
Dynamic Characteristics (Note4)						•
Input Capacitance	C <sub>lss</sub>		-	650	-	PF
Output Capacitance	Coss	V <sub>DS</sub> =50V,V <sub>GS</sub> =0V, F=1.0MHz	-	24	-	PF
Reverse Transfer Capacitance	Crss		-	20	-	PF
Switching Characteristics (Note 4)	· · ·					
Turn-on Delay Time	t <sub>d(on)</sub>		-	6	-	nS
Turn-on Rise Time	tr	$V_{DD}$ =50V, R <sub>L</sub> =19 $\Omega$	-	4	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{G}$ =3 $\Omega$	-	20	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	4	-	nS
Total Gate Charge	Qg	)/ _===0)// ====4.0	-	20		nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =50V,I <sub>D</sub> =4A, V <sub>GS</sub> =10V	-	2.1	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> =10V	-	3.3	-	nC
Drain-Source Diode Characteristics	· · ·					
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =4A	-	-	1.2	V
Diode Forward Current (Note 2)	I <sub>S</sub>		-	-	3	А

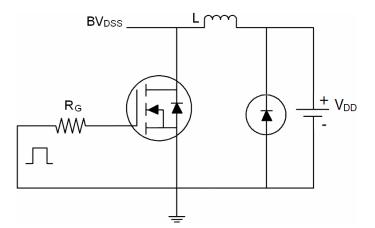
#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- Surface Mounted on FR4 Board, t ≤ 10 sec.
  Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to productio

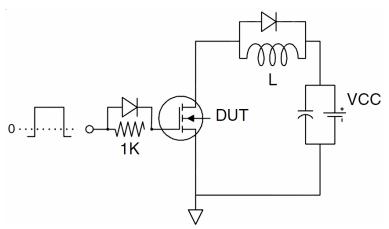


### **Test Circuit**

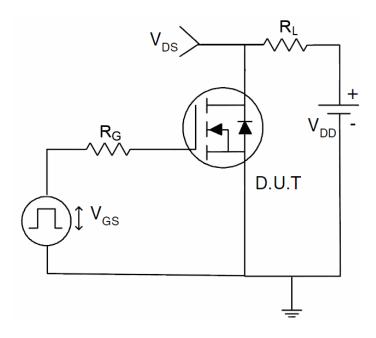
1)  $E_{AS}$  test circuit



#### 2) Gate charge test circuit

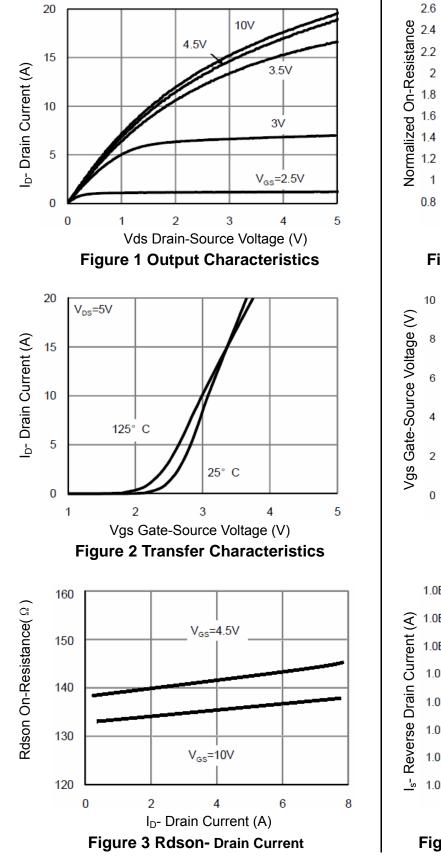


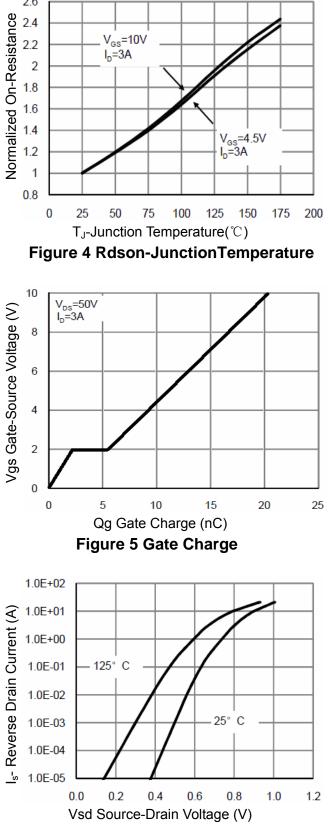
## 3) Switch Time Test Circuit





# **Typical Electrical and Thermal Characteristics (Curves)**







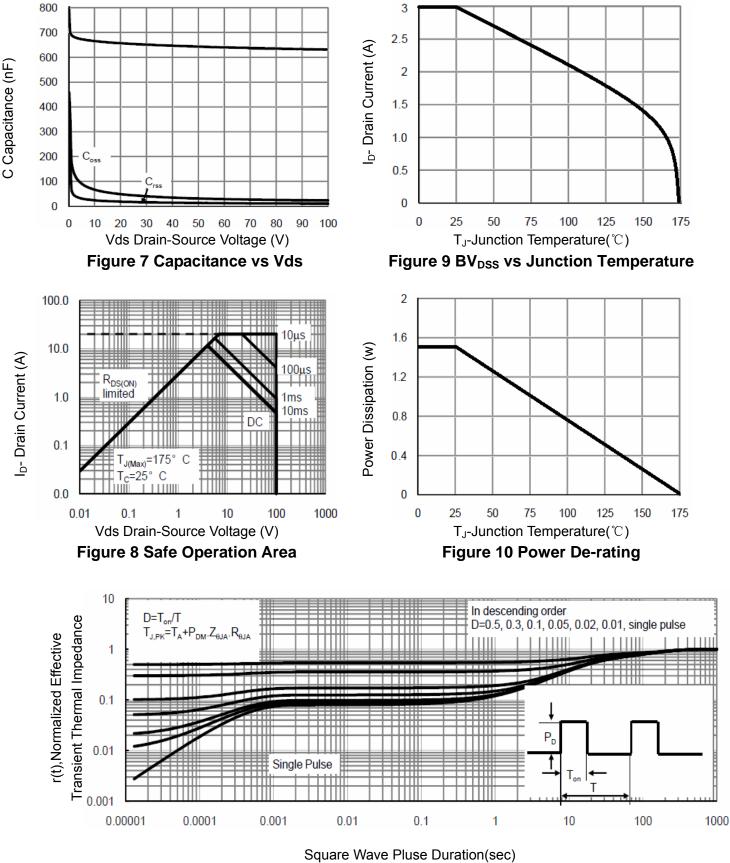
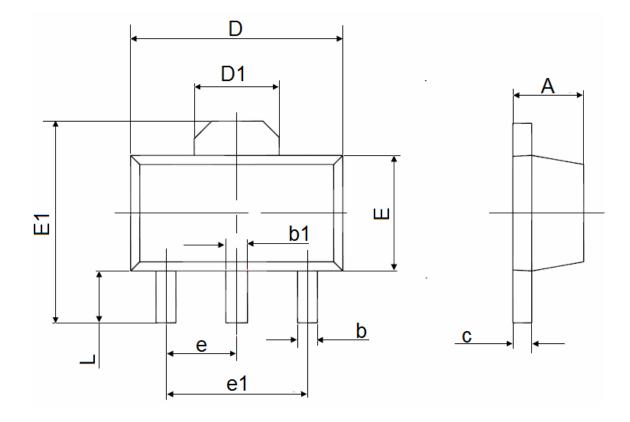


Figure 11 Normalized Maximum Transient Thermal Impedance



# SOT-89-3L Package Information



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
	Min	Max	Min	Мах	
A	1.400	1.600	0.055	0.063	
b	0.320	0.520	0.013	0.020	
b1	0.400	0.580	0.016	0.023	
с	0.350	0.440	0.014	0.017	
D	4.400	4.600	0.173	0.181	
D1	1.550	REF.	0.061 REF.		
E	2.300	2.600	0.091	0.102	
E1	3.940	4.250	0.155	0.167	
е	1.500	TYP.	0.060 TYP.		
e1	3.000 TYP.		0.118 TYP.		
L	0.900	1.200	0.035	0.047	

#### Notes

- 1. All dimensions are in millimeters.
- 2. Tolerance ±0.10mm (4 mil) unless otherwise specified
- 3. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 5 mils.
- 4. Dimension L is measured in gauge plane.
- 5. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.



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